					Application No. Applicant(s)				0	
Notice of References Cited					10/082, 089 TAKAYANA 61 Examiner Group Art Uni		$\frac{D}{\Delta}$	L		
						1	Pag	je of		
-	U.S. PATENT DOCUMENTS									
<u> </u>										
Ļ	-	DOCUMENT NO.	DATE		NAME				 	
L	<u> ^</u>	2002 10058 193 AI	. <i>1</i> .	TOSAKA it al.				430	108.23	
_		2002/0037466 AI	3/28/02	KANE	BAYASHI et	-al.		430	108.23	
43:	С									
L	D				 			ļ		
L	E			•					<u> </u>	
L	F					·				
_	G					<u> </u>				
	Н									
	1									
	J									
	κ									
	L									
Г	М	• ,			:					
FOREIGN PATENT DOCUMENTS										
*		DOCUMENT NO. DATE COUNTRY NAME CL					CLASS	SUBCLASS		
	N									
	0									
Γ	Р									
Γ	a									
┢	R									
Г	s									
	Ŧ									
NON-PATENT DOCUMENTS										
*		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)							DATE	
									`	
	υ	AMERICAN CHEMICAL SOCIETY (ACS) FILE REGISTRY NO. 56396-							2003	
	٧	AMERICAN CHEMICAL SOCIETY (ACS) FILE REGISTRY NO. 6448-96-0, COPYRIGHT 2003.							20 03	
	w	AHERICAN CHEMICAL SOCIETY (ACS) FILE REGISTRY NO. 12225-06-8, COPYRIGHT &003							2003	
	×	AMERICAN CHEMICAL SOCIETY (ACS) FILE REGISTRY NO. 67990-05-0, COPYRIGHT 2003.							2003	

*A copy of this reference is not being funished with this Office action. (See Manual of Patent Examining Procedure, Section 707.05(a).)